## Application/Control No. Applicant(s)/Patent Under Reexamination 10/623,657 ISHI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 TAN X. DINH 2627 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,205,108 b1 03-2001 Yamanaka, Yutaka 369/112.2 Α US-5,734,637 03-1998 Ootaki et al. 369/112.02 В С US-US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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